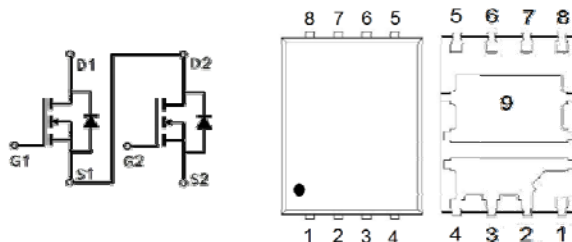


**PRODUCT SUMMARY**

	$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
Q2	30V	5.5mΩ	58A
Q1	30V	7mΩ	50A



1 : G1  
 2,3,4 : D1  
 5,6,7 : S2  
 8 : G2  
 9 : S1/D2

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25\text{ °C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	Q2	Q1	UNITS
Drain-Source Voltage		$V_{DS}$	30	30	V
Gate-Source Voltage		$V_{GS}$	±20	±20	V
Continuous Drain Current <sup>3</sup>	$T_C = 25\text{ °C}$	$I_D$	58	50	A
	$T_C = 100\text{ °C}$		36	31	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	104	81	
Continuous Drain Current	$T_A = 25\text{ °C}$	$I_D$	15	12	
	$T_A = 70\text{ °C}$		12	10	
Avalanche Current		$I_{AS}$	30	22	
Avalanche Energy	$L = 0.1\text{mH}$	$E_{AS}$	45	24	mJ
Power Dissipation	$T_C = 25\text{ °C}$	$P_D$	35	28	W
	$T_C = 100\text{ °C}$		14	11	
Power Dissipation	$T_A = 25\text{ °C}$	$P_D$	2.4	2.1	W
	$T_A = 70\text{ °C}$		1.5	1.3	
Operating Junction & Storage Temperature Range		$T_j, T_{stg}$	-55 to 150		°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL		TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient <sup>2</sup>	$R_{\theta JA}$	Q2		52	°C / W
	$R_{\theta JA}$	Q1		59	
Junction-to-Case	$R_{\theta JC}$	Q2		3.5	
	$R_{\theta JC}$	Q1		4.4	

<sup>1</sup>Pulse width limited by maximum junction temperature  $T_{J(MAX)}=150\text{ °C}$ .

<sup>2</sup>The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25\text{ °C}$ . The value in any given application depends on the user's specific board design.

<sup>3</sup>Package limitation current :Q1=25A,Q2=34A.

**ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25 °C, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT		
			MIN	TYP	MAX			
<b>STATIC</b>								
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	Q2	30		V		
			Q1	30				
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	Q2	1.3	1.7	2.3		
			Q1	1.3	1.6	2.3		
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	Q2			±100		
			Q1			±100		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V	Q2			1		
			Q1			1		
		V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 55 °C	Q2			10		
			Q1			10		
Drain-Source On-State Resistance <sup>1</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 15A	Q2		4.3	8		
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 12A	Q1		6.3	9.5		
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 15A	Q2		3.3	5.5		
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 12A	Q1		4.8	7		
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 15A	Q2		80	S		
		V <sub>DS</sub> = 5V, I <sub>D</sub> = 12A	Q1		67			
<b>DYNAMIC</b>								
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1MHz	Q2		1395	pF		
			Q1		852			
Output Capacitance	C <sub>oss</sub>		Q2		275	pF		
			Q1		162			
Reverse Transfer Capacitance	C <sub>riss</sub>		Q2		167	pF		
			Q1		103			
Gate Resistance	R <sub>g</sub>		V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V, f = 1MHz	Q2		1.3	Ω	
			Q1		2.1			
Total Gate Charge <sup>2</sup>	Q <sub>g</sub>		Q2 V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 15A Q1 V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 12A	V <sub>GS</sub> = 10V	Q2		29.6	nC
				V <sub>GS</sub> = 10V	Q1		18.6	
		V <sub>GS</sub> = 4.5V		Q2		15.7		
				Q1		10		
Gate-Source Charge <sup>2</sup>	Q <sub>gs</sub>	Q2			4.1	nC		
		Q1			2			
Gate-Drain Charge <sup>2</sup>	Q <sub>gd</sub>	Q2			8.5	nC		
		Q1			5.4			

Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	Q2 $V_{DS} = 15V,$ $I_D \cong 15A, V_{GS} = 10V, R_{GEN} = 6\Omega$ Q1 $V_{DS} = 15V,$ $I_D \cong 12A, V_{GS} = 10V, R_{GEN} = 6\Omega$	Q2		27		nS
			Q1		18		
Rise Time <sup>2</sup>	$t_r$		Q2		16		
			Q1		13		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$		Q2		66		
			Q1		33		
Fall Time <sup>2</sup>	$t_f$		Q2		23		
			Q1		15		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25\text{ }^\circ\text{C}</math>)</b>							
Continuous Current <sup>3</sup>	$I_S$		Q2			29	A
			Q1			23	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 15A, V_{GS} = 0V$	Q2			1.2	V
		$I_F = 12A, V_{GS} = 0V$	Q1			1.2	
Reverse Recovery Time	$t_{rr}$	Q2	Q2		21.3		nS
		$I_F = 15A, di_F/dt = 100A / \mu S$	Q1		15.8		
Reverse Recovery Charge	$Q_{rr}$	Q1	Q2		8.8		nC
		$I_F = 12A, di_F/dt = 100A / \mu S$	Q1		5.1		

<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

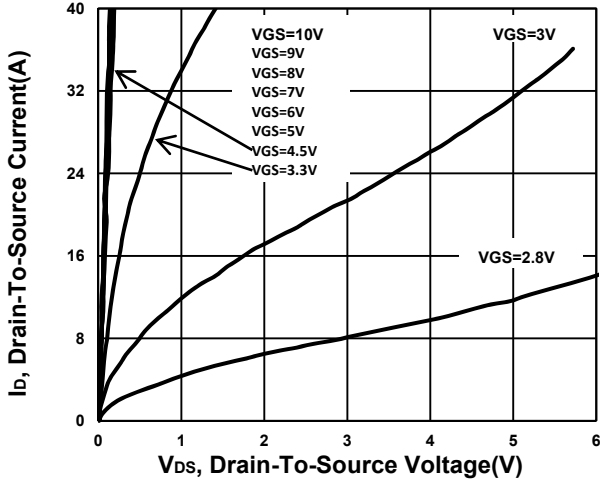
<sup>2</sup>Independent of operating temperature.

<sup>3</sup>Package limitation current : Q1=25A, Q2=34A.

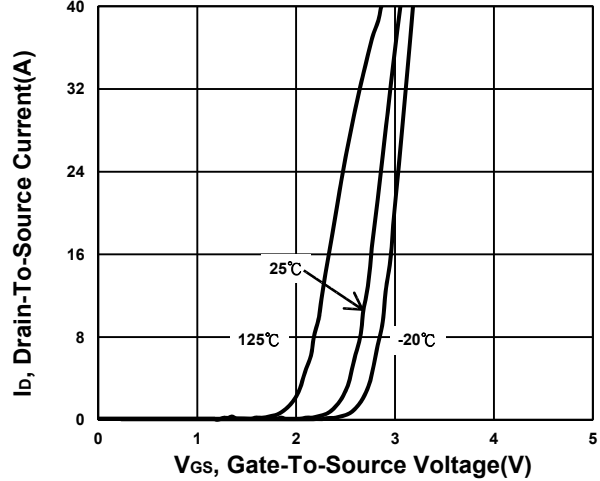
**TYPICAL PERFORMANCE CHARACTERISTICS**

**Q2**

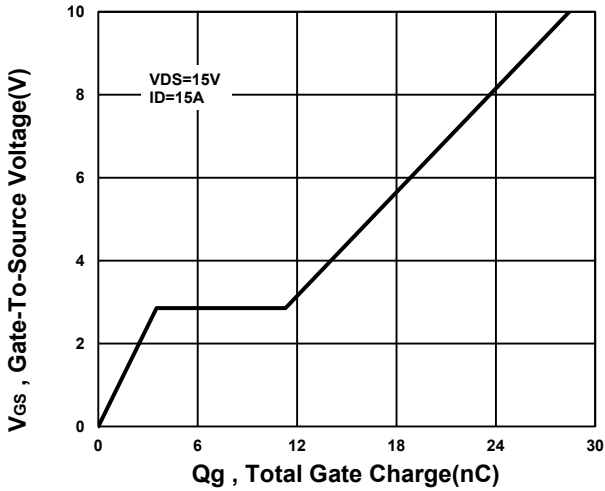
**Output Characteristics**



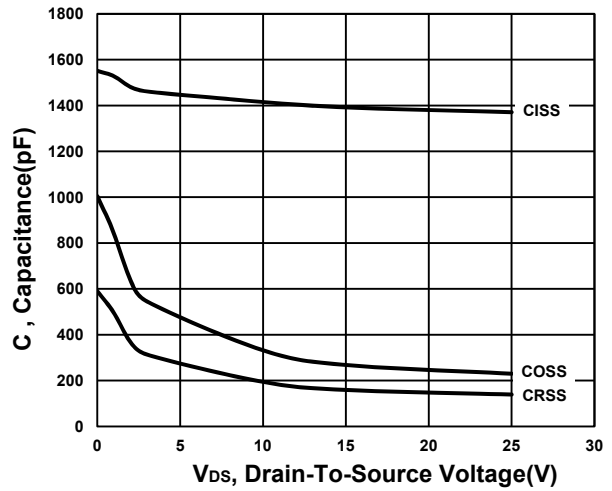
**Transfer Characteristics**



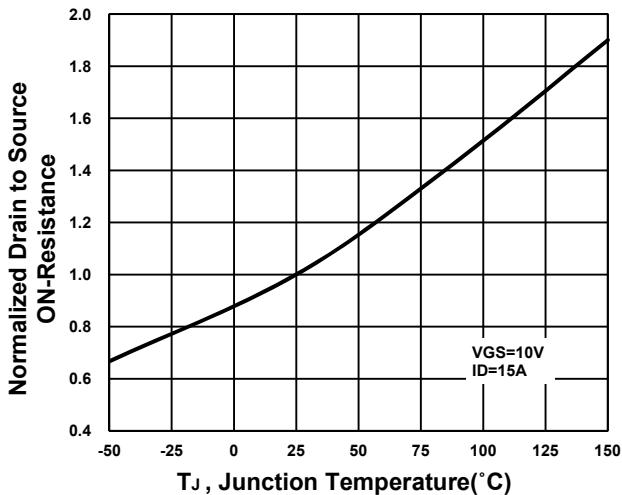
**Gate charge Characteristics**



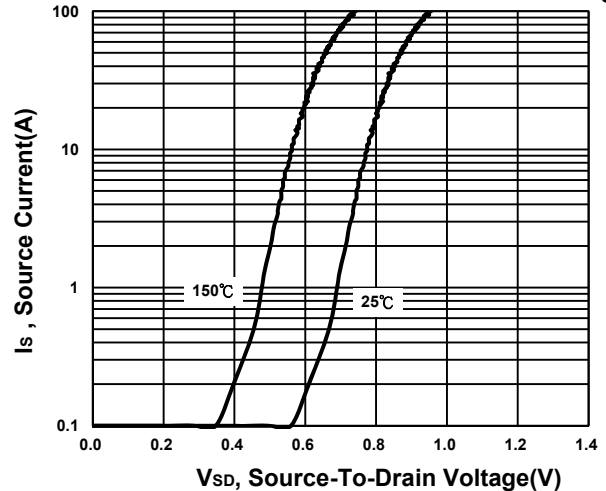
**Capacitance Characteristic**



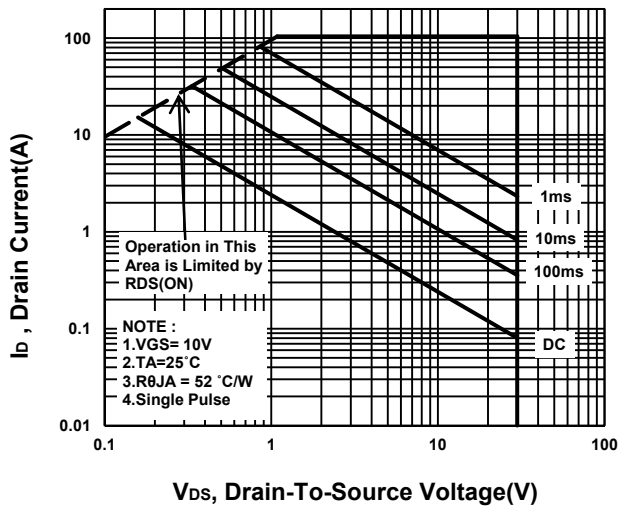
**On-Resistance VS Temperature**



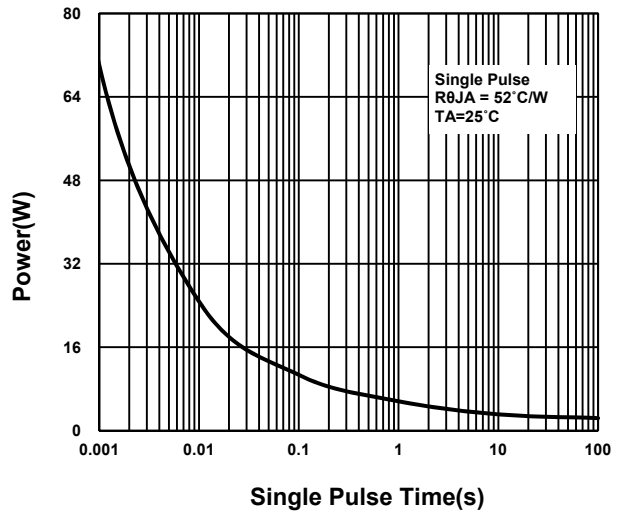
**Source-Drain Diode Forward Voltage**



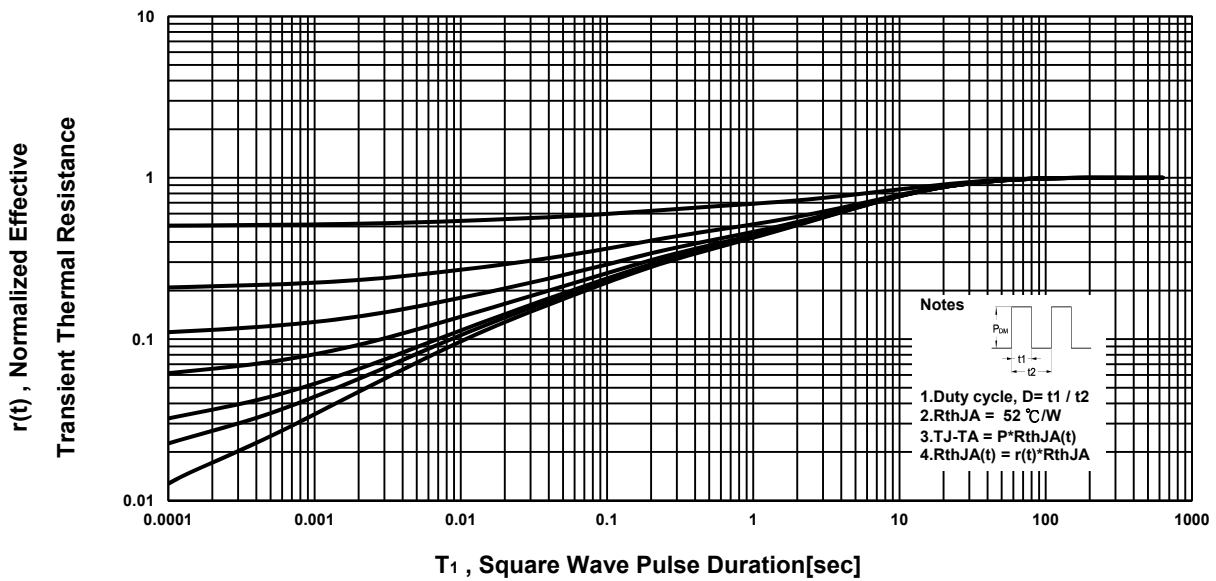
**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**

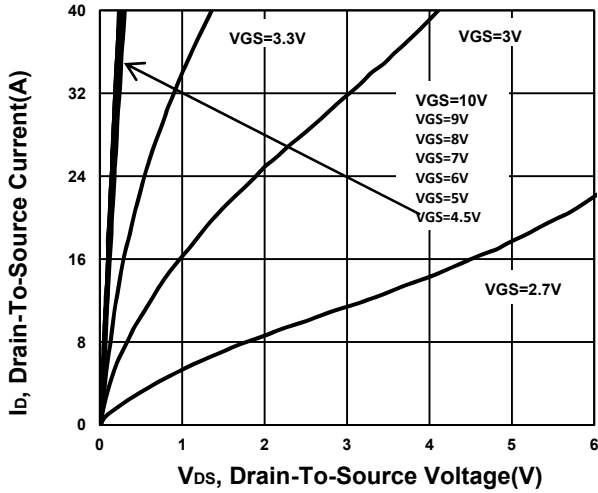


**Transient Thermal Response Curve**

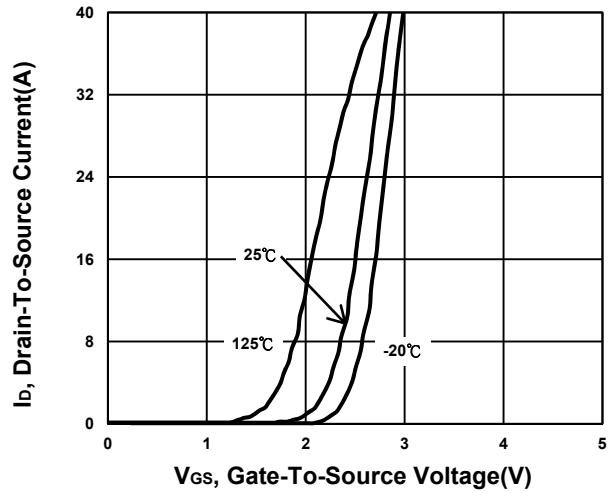


**Q1**

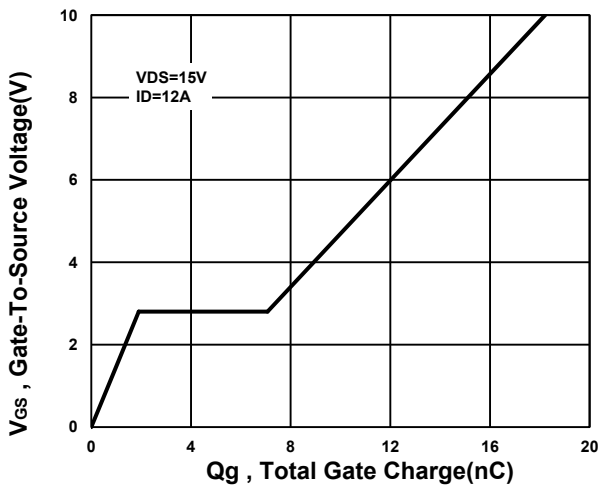
**Output Characteristics**



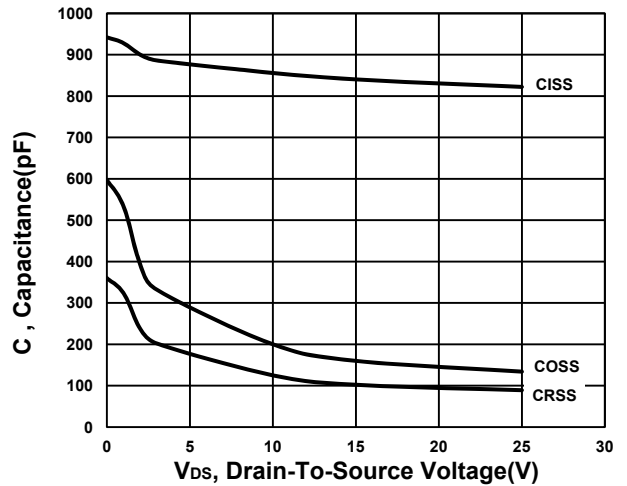
**Transfer Characteristics**



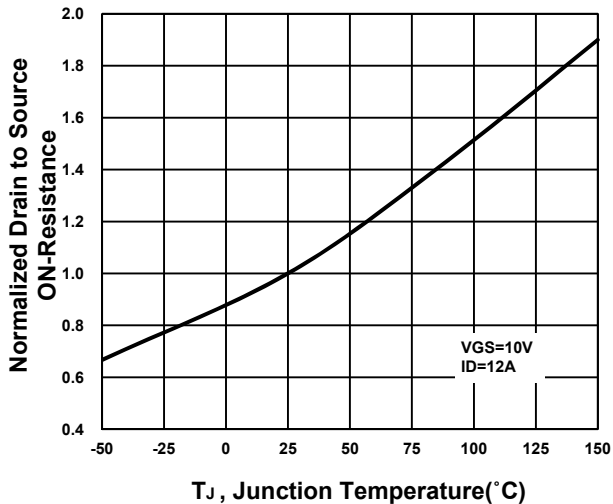
**Gate charge Characteristics**



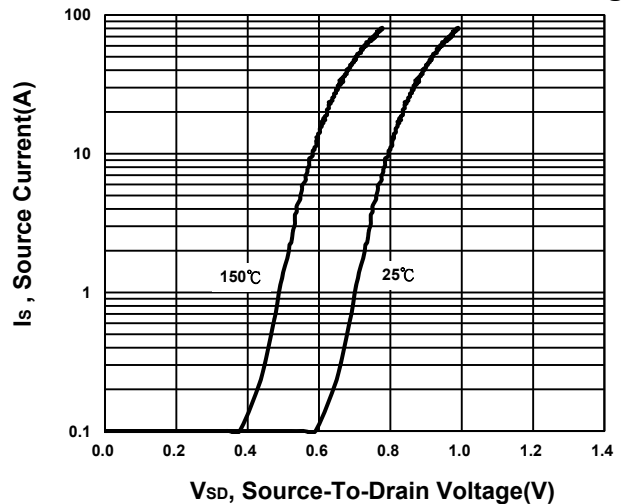
**Capacitance Characteristic**



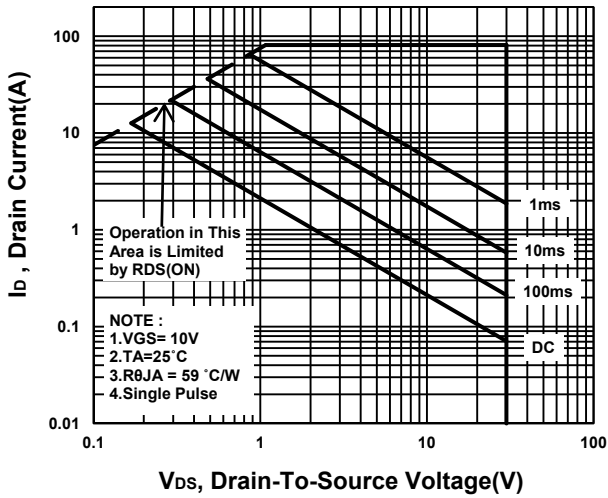
**On-Resistance VS Temperature**



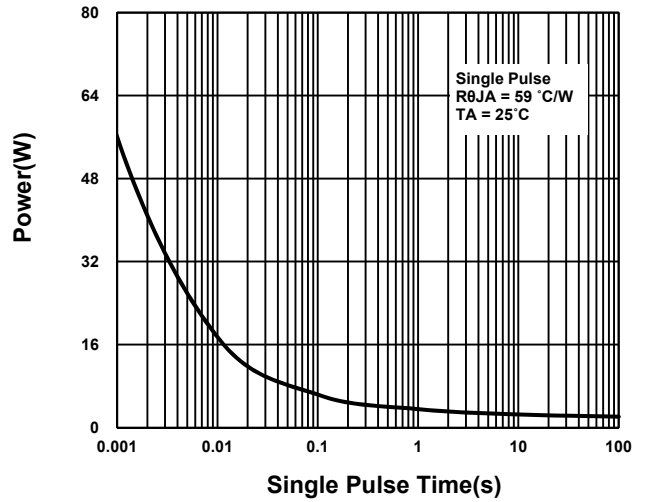
**Source-Drain Diode Forward Voltage**



**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**



**Transient Thermal Response Curve**

